MOSFET, N-Channel Shielded Gate, POWERTRENCH®

80 V, 116 A, 4.2 mΩ

General Description

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced POWERTRENCH® process that incorporates Shielded Gate technology. This process has been optimized to minimise on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 4.2 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 37 \text{ A}$
- Max $r_{DS(on)} = 6.1 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 29 \text{ A}$
- 50% Lower Qrr than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

Typical Applications

- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar

MOSFET MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V _{DS}	Drain to Source Voltage	80	٧
V _{GS}	Gate to Source Voltage	±20	٧
I _D	Drain Current – Continuous $T_C = 25^{\circ}C$ (Note 5)	116	Α
	Continuous T_C = 100°C (Note 5)	73	
	− Continuous T _A = 25°C (Note 1a)	17	
	- Pulsed (Note 4)	633	
E _{AS}	Single Pulse Avalanche Energy (Note 3)	384	mJ
P _D	Power dissipation T _C = 25°C	113.6	W
	Power dissipation T _A = 25°C (Note 1a)	2.5	
T _{J,} T _{STG}	Operating and Storage Junction Temperature Range	–55 to +150	°C

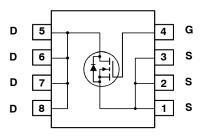
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



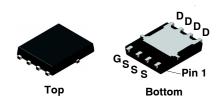
ON Semiconductor®

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ELECTRICAL CONNECTION



N-Channel MOSFET



Power 56 (PQFN8 5x6) CASE 483AE

MARKING DIAGRAM

\$Y&Z&3&K **FDMS** 4D5N08LC

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code &K = Lot Code

FDMS4D5N08LC = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	1.1	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Shipping [†]	
FDMS4D5N08LC	FDMS4D5N08LC	PQFN8 5×6 (Pb-Free/Halogen Free)	3000 Units/ Tape & Reel	

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRIC	AL CHARACTERISTICS (T _J = 25°C unle	ess otherwise noted)				
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C		66		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 64 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate-to-Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
ON CHARAC	CTERISTICS					
V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 210 μA	1.0	1.4	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 210 μA, referenced to 25°C		-5.1		mV/°C
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 37 A		3.2	4.2	mΩ
		V _{GS} = 4.5 V, I _D = 29 A		4.5	6.1	
		V _{GS} = 10 V, I _D = 37 A, T _J = 125°C		5.7	7.5	
9FS	Forward Transconductance	V _{DS} = 5 V, I _D = 37 A		135		S
DYNAMIC C	HARACTERISTICS					
C _{iss}	Input Capacitance	V _{DS} = 40 V, V _{GS} = 0 V, f = 1MHz		3640	5100	
C _{oss}	Output Capacitance			834	1170	рF
C _{rss}	Reverse Transfer Capacitance			39	65	
R_g	Gate Resistance		0.1	0.6	1.1	Ω
SWITCHING	CHARACTERISTICS					
td _(on)	Turn – On Delay Time	V _{DD} = 40 V, I _D = 37 A,		13	23	ns
t _r	Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		19	34	
t _{D(off)}	Turn – Off Delay Time			59	94	
t _f	Fall Time			17	30	
Qg	Total Gate Charge	V _{GS} = 0V to 10 V		51	71	nC
Qg	Total Gate Charge	V _{GS} = 0V to 4.5 V		24	34	
Q _{gs}	Gate to Source Charge	V _{DD} = 40 V, i _D = 37 A		8		
Q_{gd}	Gate to Drain "Miller" Charge			6		
Q _{oss}	Output Charge	V _{DD} = 40 V, V _{GS} = 0 V		51		nC
Q _{sync}	Total Gate Charge Sync.	V _{DS} = 0 V, I _D = 37 A		46		

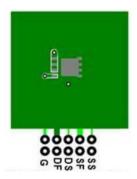
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHARACTERISTICS							
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.1 A (Note 2)		0.7	1.2	V	
		V _{GS} = 0 V, I _S = 37 A (Note 2)		0.8	1.3		
t _{rr}	Reverse Recovery Time	I _F = 18 A, di/dt = 300 A/μs		22	36	ns	
Q _{rr}	Reverse Recovery Charge	1		38	61	nC	
t _{rr}	Reverse Recovery Time	I _F = 18 A, di/dt = 1000 A/μs		17	27	ns	
Q _{rr}	Reverse Recovery Charge			82	132	nC	

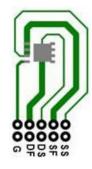
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTES:

 R_{θ,JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. R_{θCA} is determined by the user's board design.



 a) 50°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- E_{AS} of 384 mJ is based on starting T_J = 25°C; N-ch: L = 3 mH, I_{AS} = 16 A, V_{DD} = 72 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 41 A, V_{GS} = 10 V.
- 4. Pulsed I_D please refer to Figure 11 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS T_J = 25°C unless otherwise noted

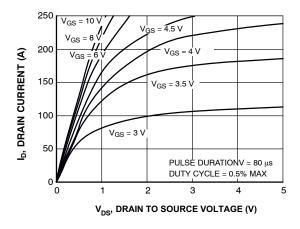


Figure 1. On Region Characteristics

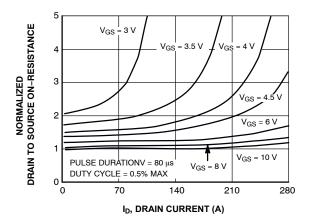


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

TYPICAL CHARACTERISTICS T_J = 25°C unless otherwise noted (continued)

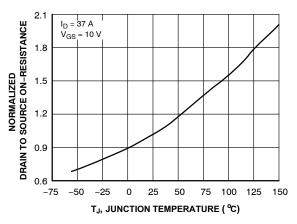


Figure 3. Normalized On Resistance vs. Junction Temperature

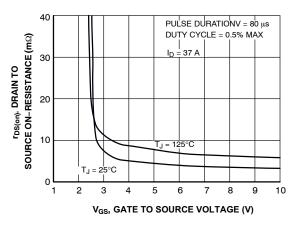


Figure 4. On-Resistance vs. Gate to Source Voltage

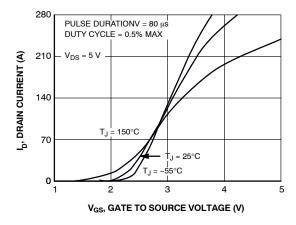


Figure 5. Transfer Characteristics

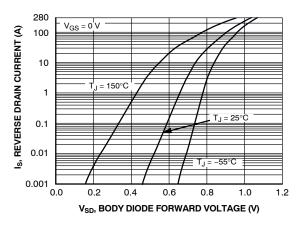


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

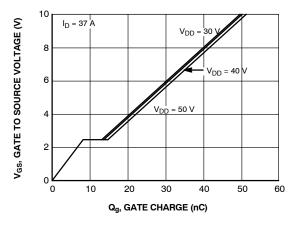


Figure 7. Gate Charge Characteristics

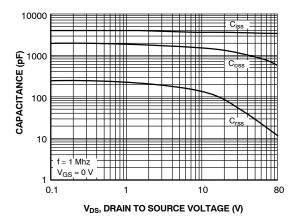


Figure 8. Capacitance vs. Drain to Source Voltage

TYPICAL CHARACTERISTICS T_J = 25°C unless otherwise noted (continued)

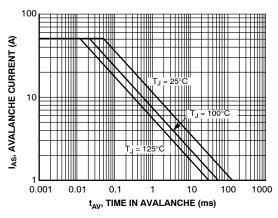


Figure 9. Unclamped Inductive Switching Capability

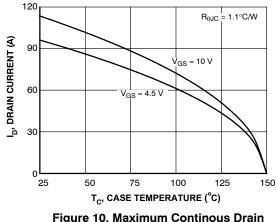


Figure 10. Maximum Continous Drain Current vs. Case Temperature

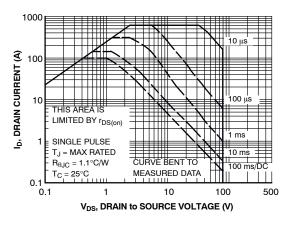


Figure 11. Unclamped Inductive Switching Capability

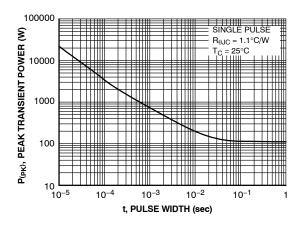


Figure 12. Maximum Continuous Drain Current vs. Case Temperature

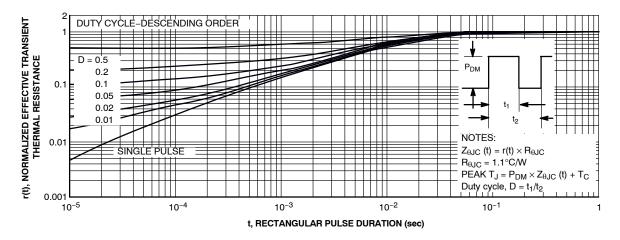
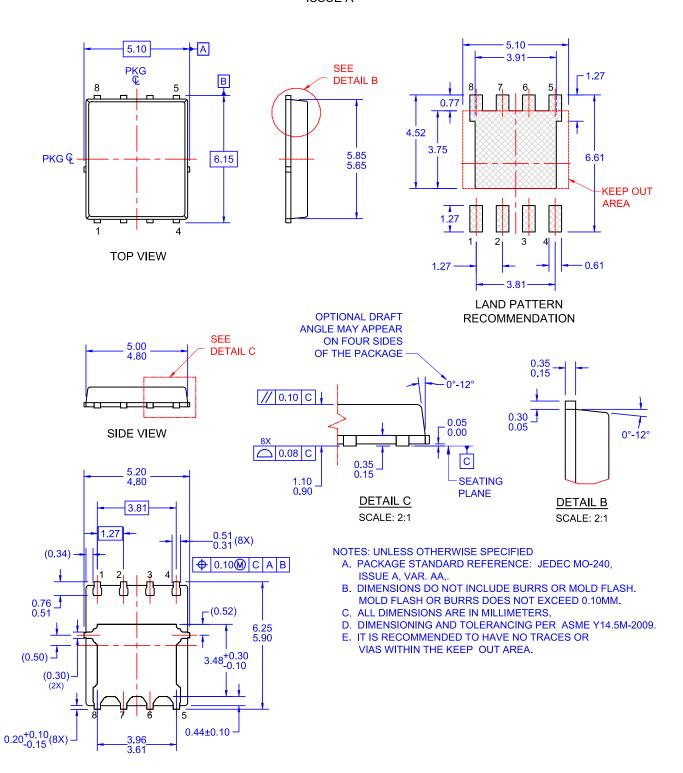


Figure 13. Junction-to-Case Transient Thermal Response Curve

PACKAGE DIMENSIONS

PQFN8 5X6, 1.27P CASE 483AE ISSUE A



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